

Notice of References Cited	Application/Control No. 10/611,995	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,478,897	11-2002	Izumida et al.	148/428
	B	US-6,475,427	11-2002	Deshmukh et al.	419/8
	C	US-6,200,688	03-2001	Liang et al.	428/544
	D	US-5,938,543	08-1999	McGeeney et al.	473/324
	E	US-4,692,305	09-1987	Rangaswamy et al.	420/436
	F	US-2003/0000341	01-2003	Amick, Darryl D.	75/352
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	59-70744	04-1984	Japan	Yabuki et al.	420/448
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Derwent Abstract 2003-842132 for Patent Document No. TW537916A June 2003
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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